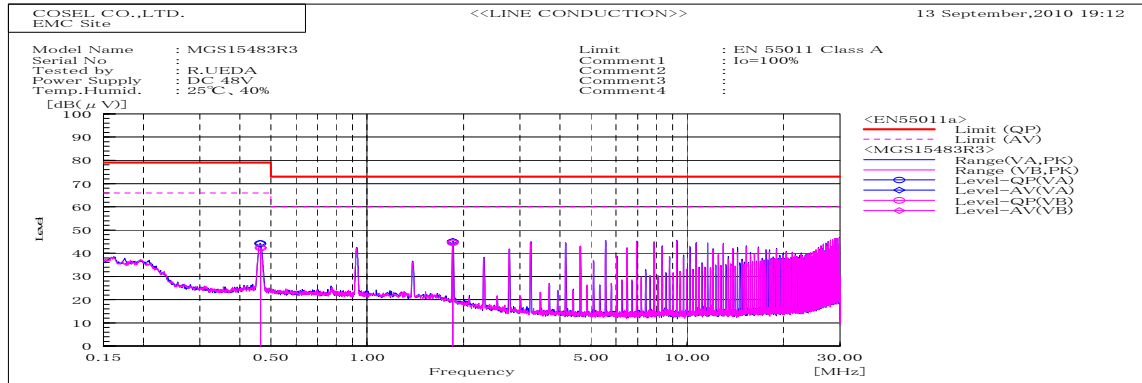
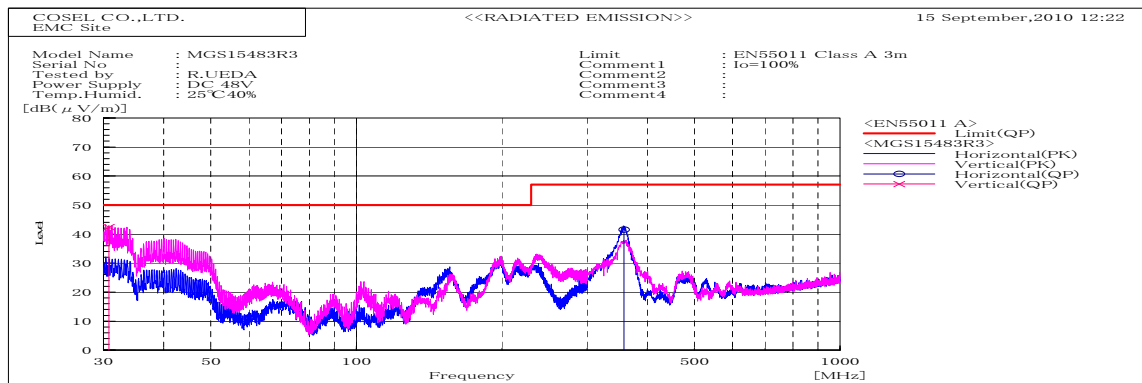


DATA SHEET		Date	21-Sep-10
Model	MGS15483R3	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	R.Ueda



Frequency MHz	Harm	Line Phase	Reading dB(uV)		Factor dB	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.46344		VA	34.1	34.2	10.1	44.2	44.3	79	66	34.8	21.7	Pass	
0.46513		VB	32.3	32.4	10	42.3	42.4	79	66	36.7	23.6	Pass	
1.85118		VA	34.8	35.1	10.1	44.9	45.2	73	60	28.1	14.8	Pass	
1.85181		VB	34.4	34.7	10.1	44.5	44.8	73	60	28.5	15.2	Pass	



Frequency MHz	Polarization	Stability	Reading dB(uV)		Space Loss dB	Level dB(mW)		Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	AV						
30.773	V	Stable	56.2	-13.8		42.4		50	7.6	Pass	106	34	
358.023	H	Stable	57.5	-16		41.5		57	15.5	Pass	102	353	

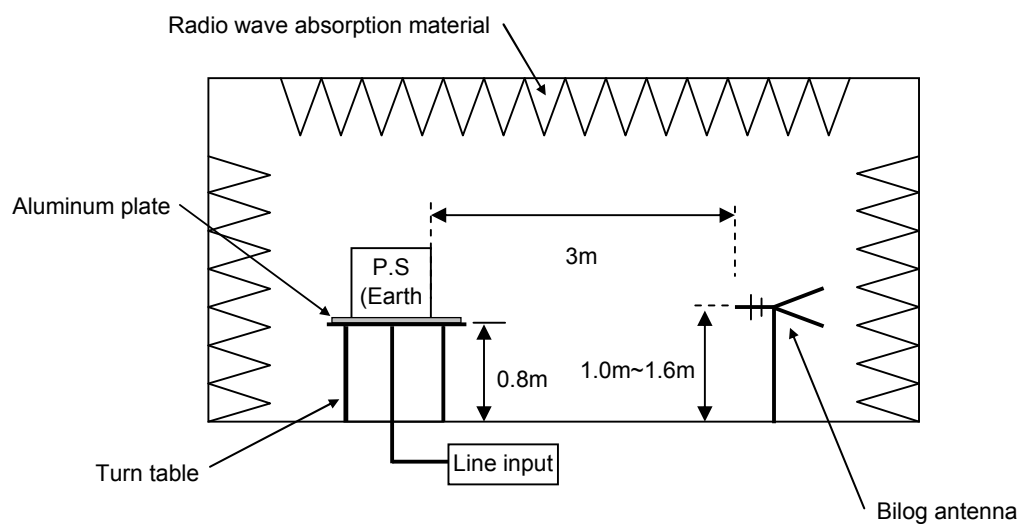
# DATA SHEET

Model	Circuit used for measurement
Test	EMI Line conduction & Radiated emission

## 1. Line conduction



## 2. Radiated emission



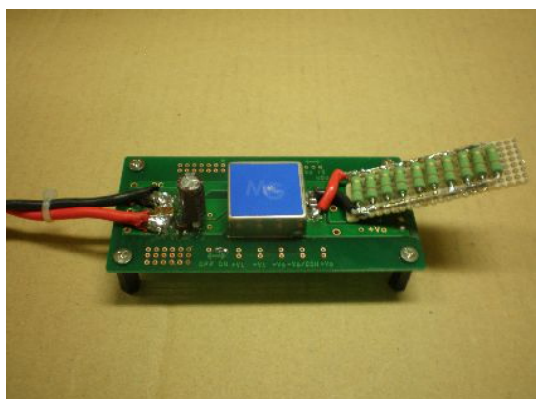


## Conditions

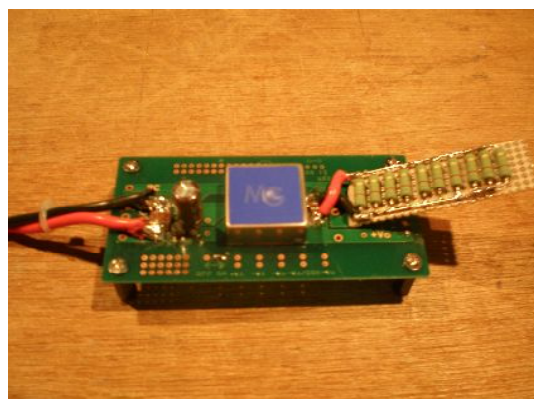
Test : EMI  
Model Name : MGS1548□□/MGW1548□□

○Photographs of Test Set-Up

### LINE CONDUCTION



### RADIATED EMISSION



○Testing circuitry

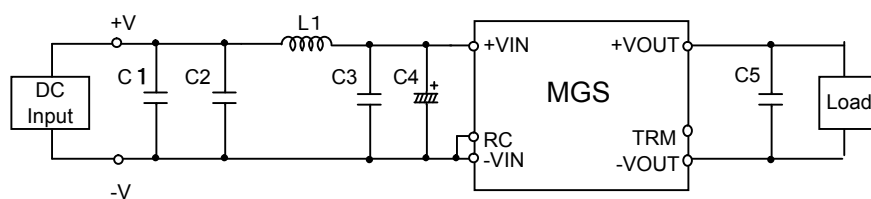


Fig.1 Testing circuitry 1

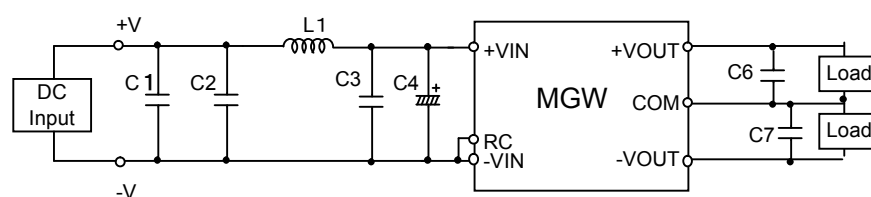


Fig.2 Testing circuitry 2

L1	: 10 $\mu$ H	CI4C-100	(KORIN ELECTRONICS)
C1,C2,C3	: 100V	2.2 $\mu$ F	C4532JB2A225MT (TDK)
C4	: 80V	47 $\mu$ F	LXV80VB47M (NIPPON CHEMI-CON)
C5,C6,C7	: 25V	22 $\mu$ F	CM32X5R226K25A (KYOCERA)